## nexperia

## **Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2022

Based on structural similarity

| Suppli        | ier   | User Part Number   |                             |           |            |              |  |  |  |
|---------------|---|--|-----------------------------|-----------|------------|--------------|--|--|--|
| Nexperia B.V. |   | 74AHCT1G02GW   | 74AHCT1G02GW                |           |            |              |  |  |  |
| Part D        | escription: Single 2-input N  | NOR gate; TTL enabled  |                             |           |            |              |  |  |  |
| Pro           | nction Family: AHC(T)<br>Icess family: Super micron<br>Ickage family: TSSOP |  |                             |           |            |              |  |  |  |
| JESD4         | 7 Test  | Test Conditions  | Duration                    | # Lots    | # Quantity | #<br>Rejects |  |  |  |
| # 1           | <b>TEST</b><br>Pre- and Post-Stress<br>Electrical Test                      | Tamb = 25 °C   | N/A                         | see below | all parts  | see<br>below |  |  |  |
| # 2           | <b>PC</b><br>Preconditioning  | JESD22-A113<br>MSL 1   | N/A                         | 1070      | 83683      | 0            |  |  |  |
| # 5a          | HTOL EFR<br>High Temperature<br>Operating Life Extrinsic                    | JESD22-A108<br>Tj = 150°C<br>$V_{CCMAX} \le V \le 1.2*V_{CCMAX}$                       | 48 hours<br>or<br>168 hours | 136       | 39090      | 0            |  |  |  |
| # 5b          | HTOL IFR<br>High Temperature<br>Operating Life Intrinsic                    | JESD22-A108<br>Tj = 150°C<br>V <sub>CCMAX</sub> $\leq$ V $\leq$ 1.2*V <sub>CCMAX</sub> | ≥500 hours                  | 84        | 5695       | 0            |  |  |  |
| # 7           | TC<br>Temperature Cycling   | JESD22-A104<br>-65 °C to 150°C   | ≥500 cycles                 | 549       | 43127      | 0            |  |  |  |
| # 9           | uHAST / HAST<br>unbiased or biased High<br>Accelerated Stress Test          | JESD22-A101<br>Tamb = 130 °C,<br>RH = 85%, V = V <sub>CCMAX</sub>                      | 96 hours                    | 521       | 40556      | 0            |  |  |  |

## **Calculation of PPM, FIT and MTTF**

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above) Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic(HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Product<br>Family | Package<br>Family | Quantity | Rejects | Extrinsic<br>Failure Rate (PPM) | Intrinsic<br>Failure Rate (FIT) | MTTF (hrs) |
|-------------------|-------------------|----------|---------|---------------------------------|---------------------------------|------------|
| AHC(T)            | TSSOP             | 5695     | 0       | 24                              | 0.6                             | 1.74 E+09  |

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